



University of Antwerp
Faculty of Science



MFEM Workshop 2024 @ LLNL

Simulating atom probe tomography using MFEM

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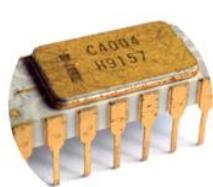
Metrology of modern tech

Moore's Law



1965

10000nm



1971

1000nm



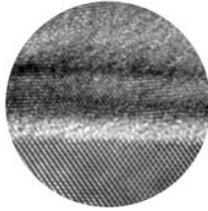
1984

100nm



2003

45nm



2007

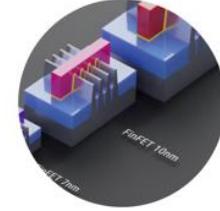
finFET

22nm



2011

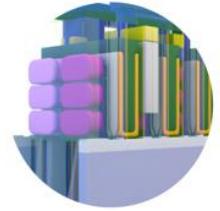
10nm



2016

GAAFET

3nm



2022

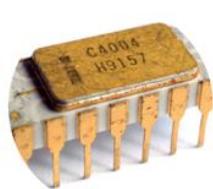
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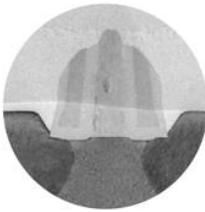
1971

1000nm



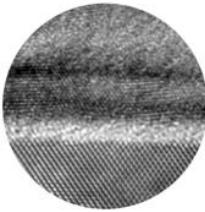
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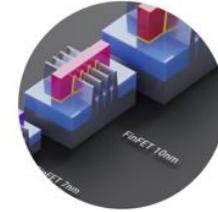
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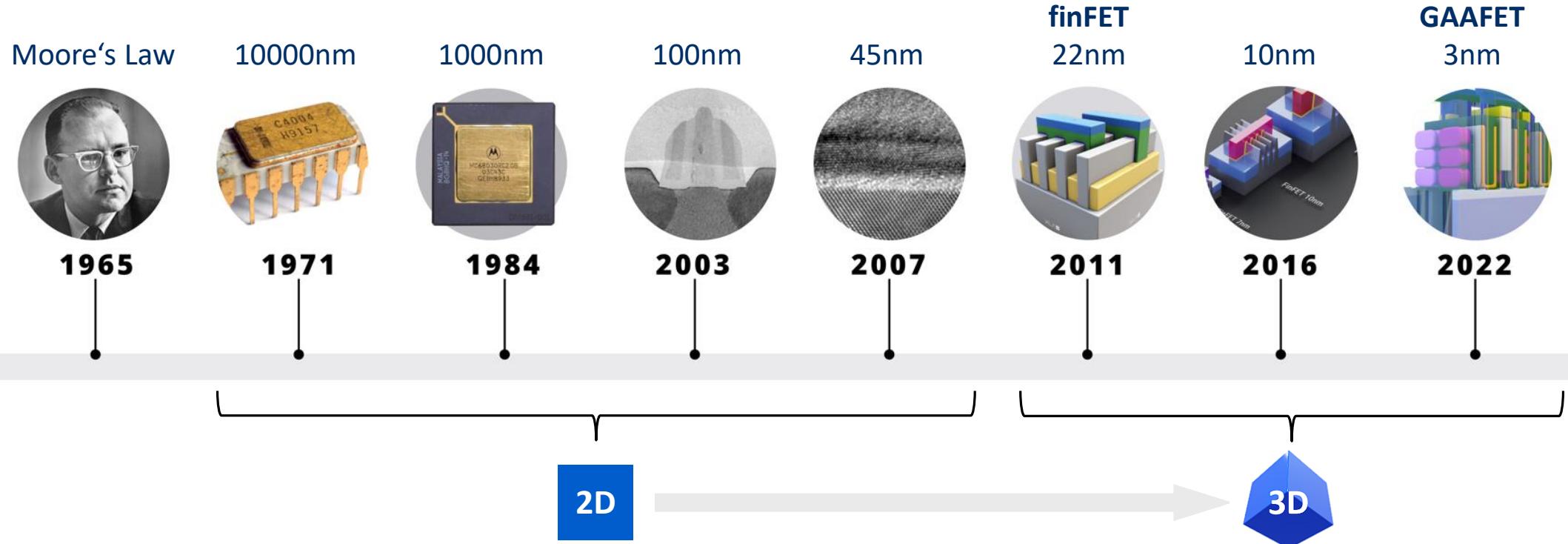
3nm



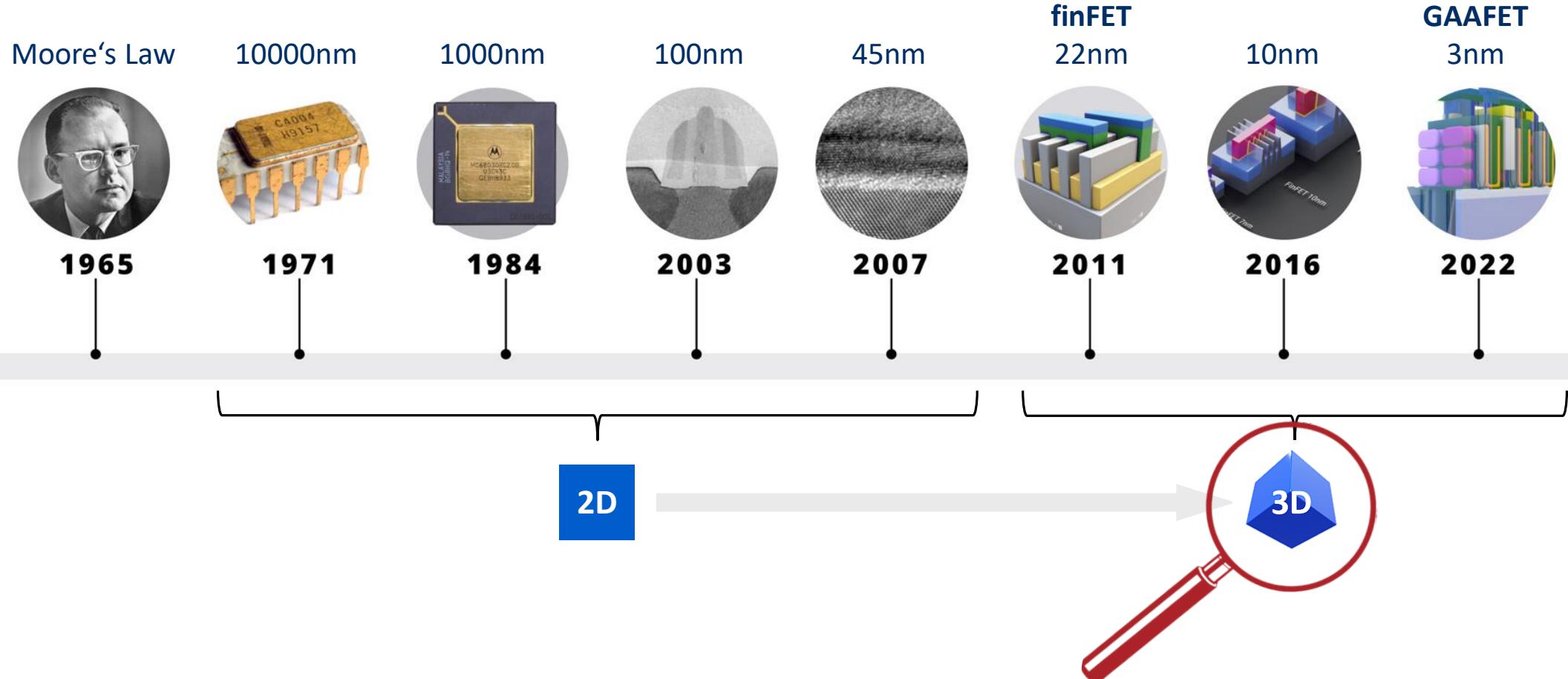
2022

2D

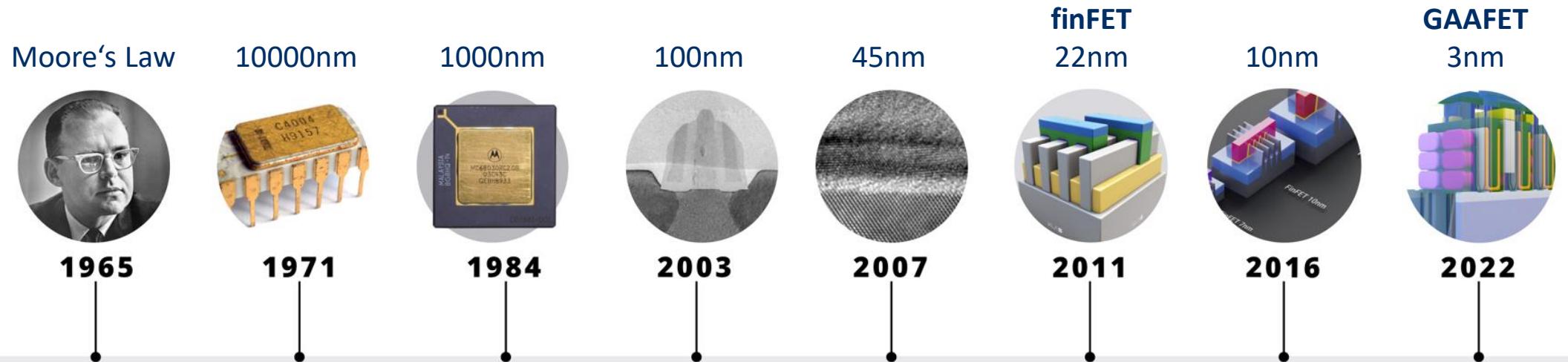
Metrology of modern tech



Metrology of modern tech

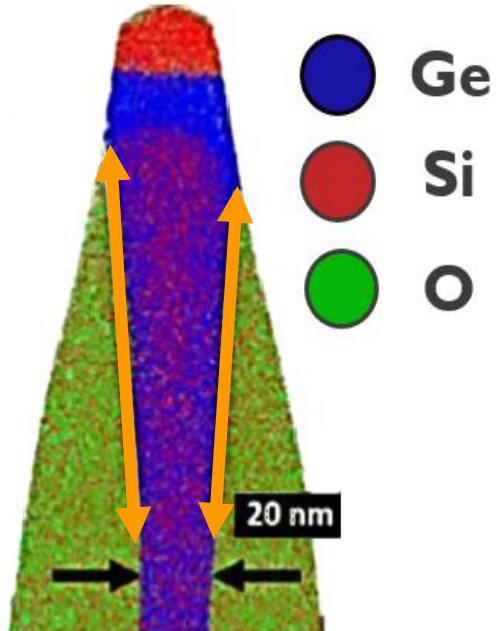


Metrology of modern tech



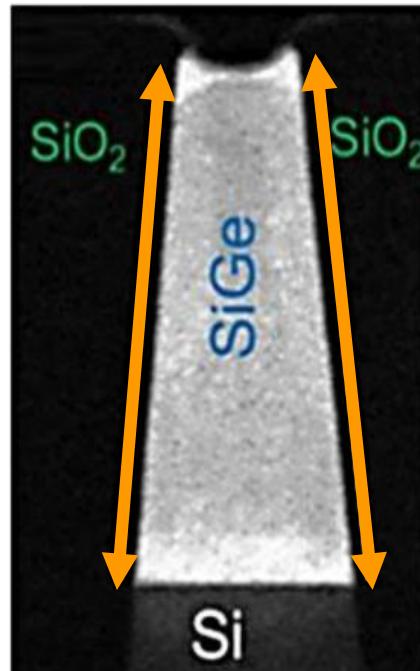
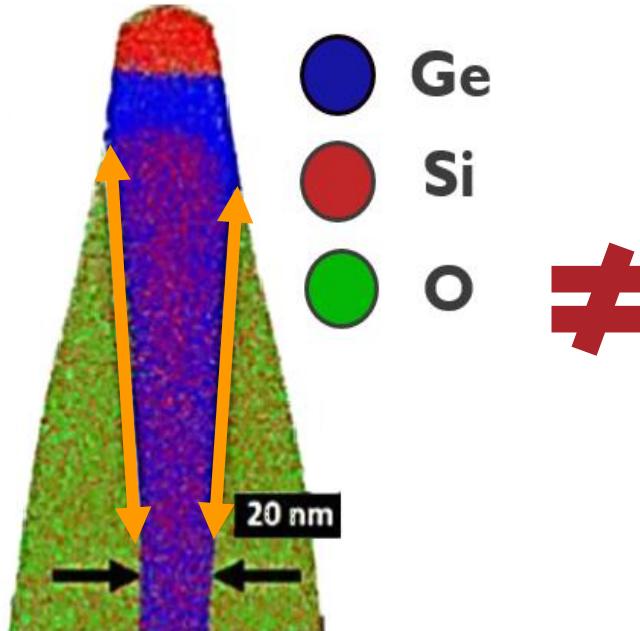
**Atom probe tomography
(APT)**

Problem statement



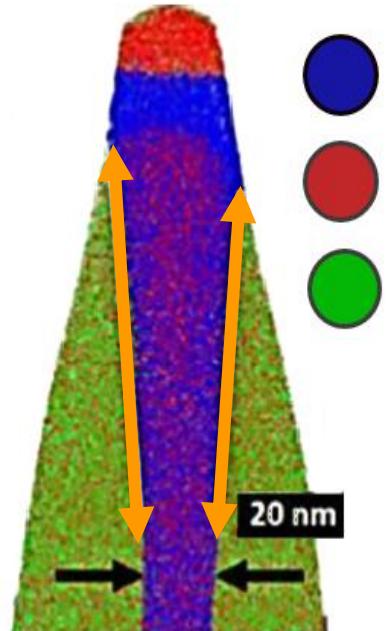
APT

Problem statement



\neq

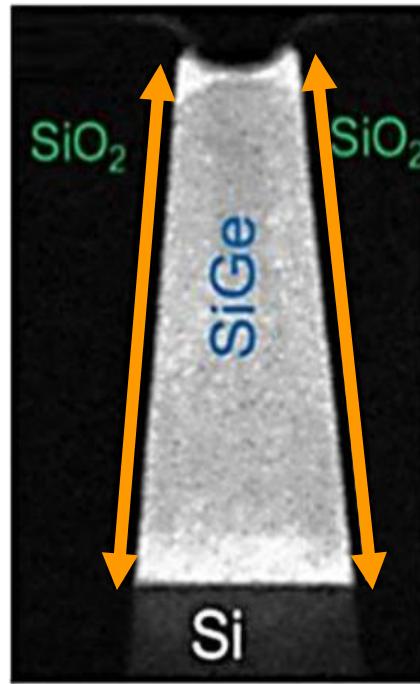
Problem statement



APT

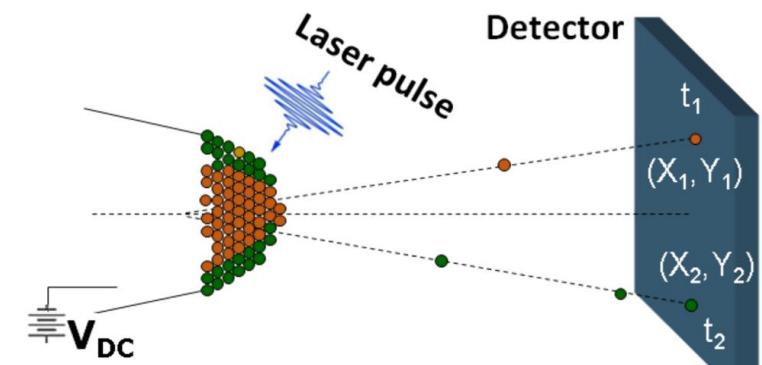


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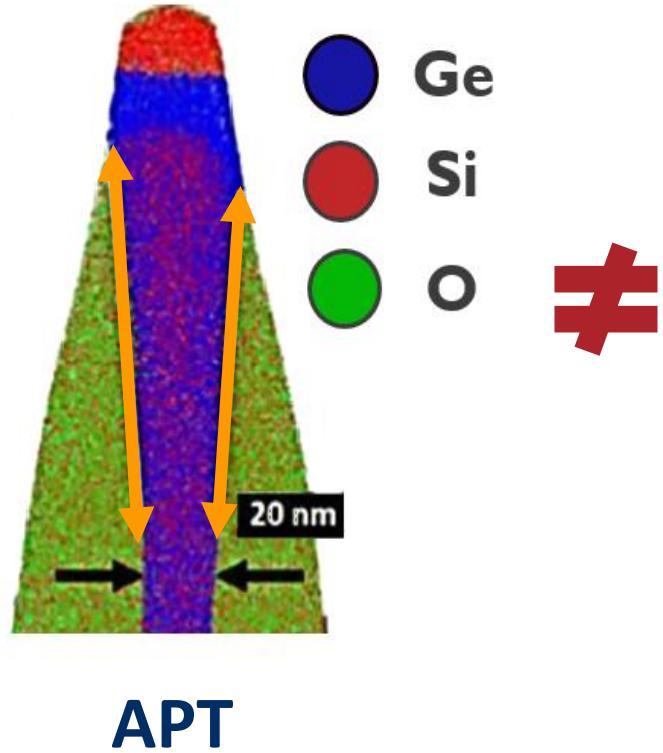


TEM

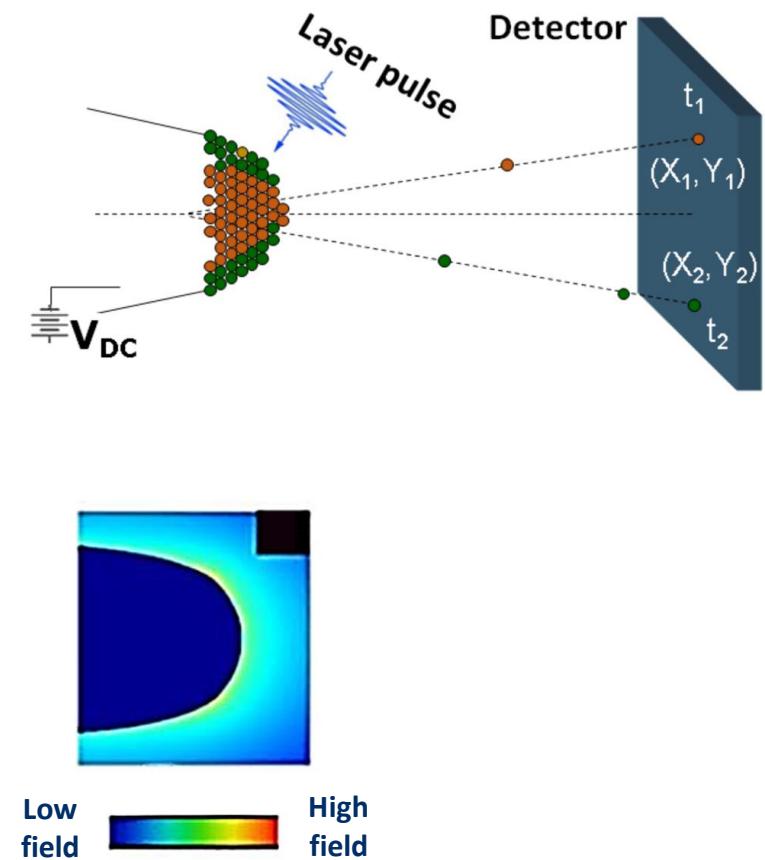
But why?



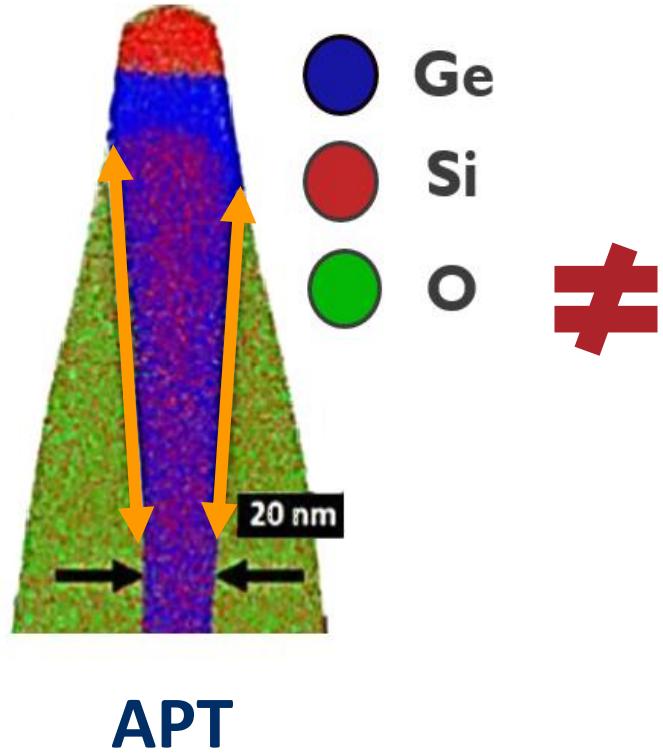
Problem statement



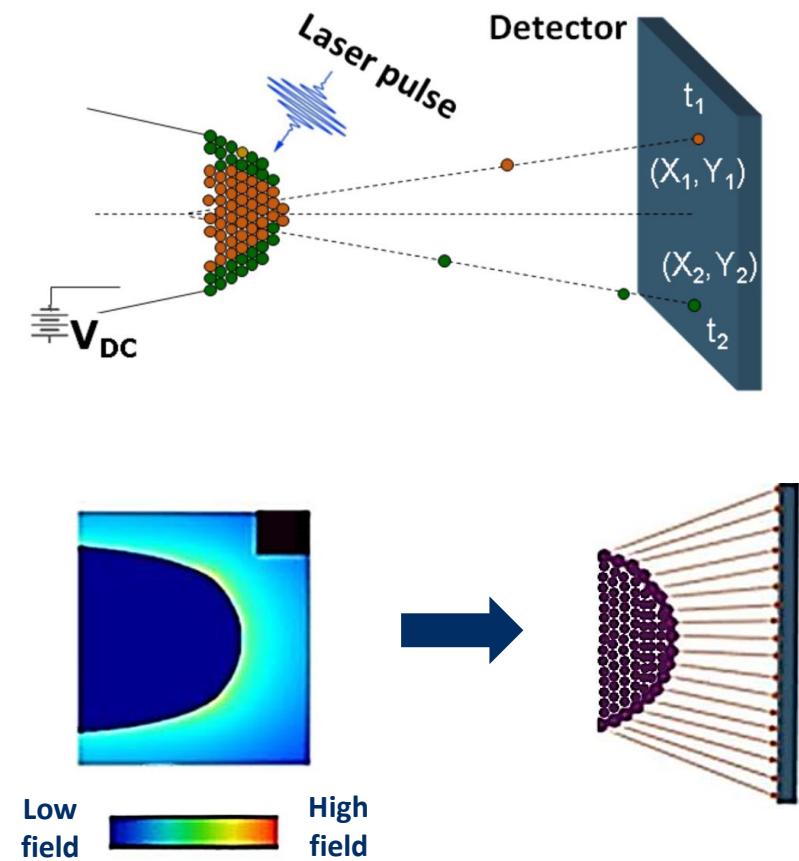
But why?



Problem statement

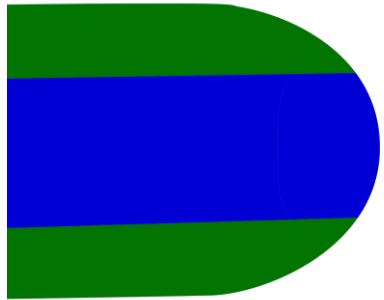


But why?

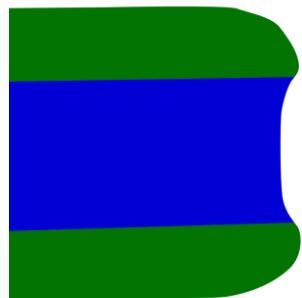


Complex reality of APT

Material effects

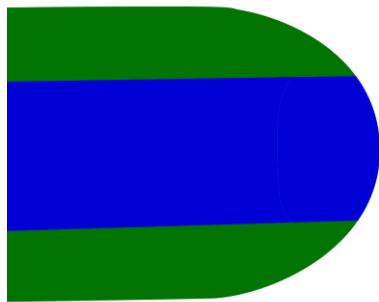


time ↴

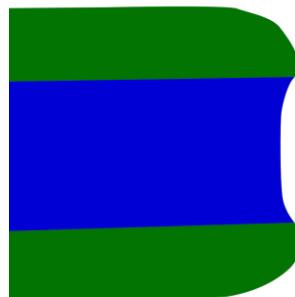


Complex reality of APT

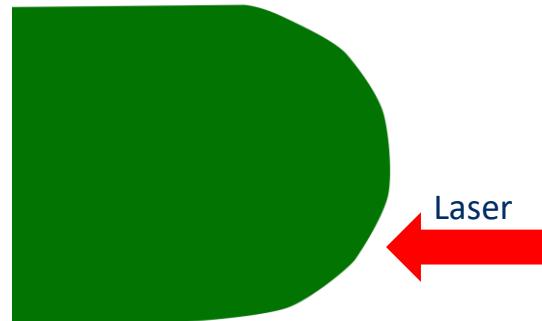
Material effects



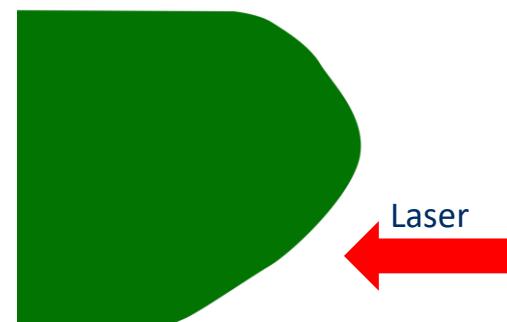
time ↴



Laser effects

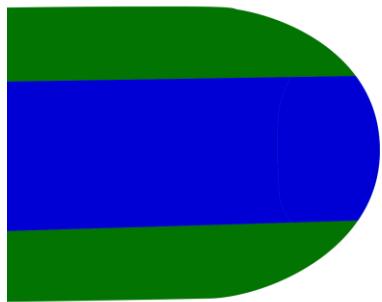


time ↴

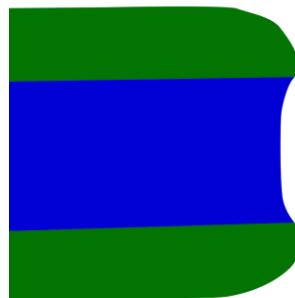


Complex reality of APT

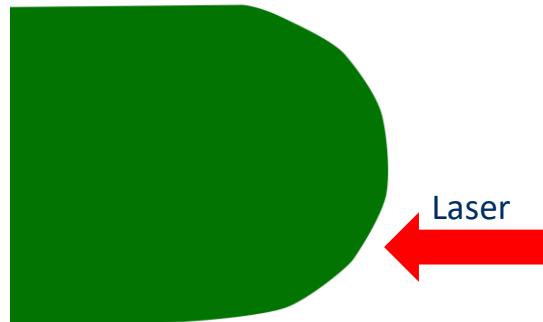
Material effects



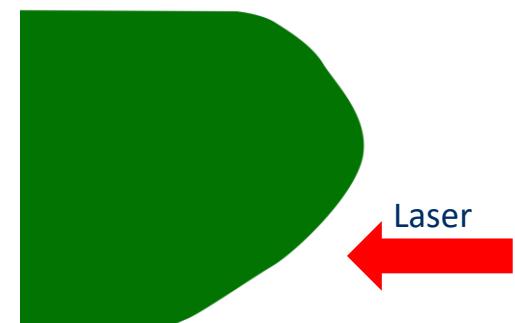
time ⏲



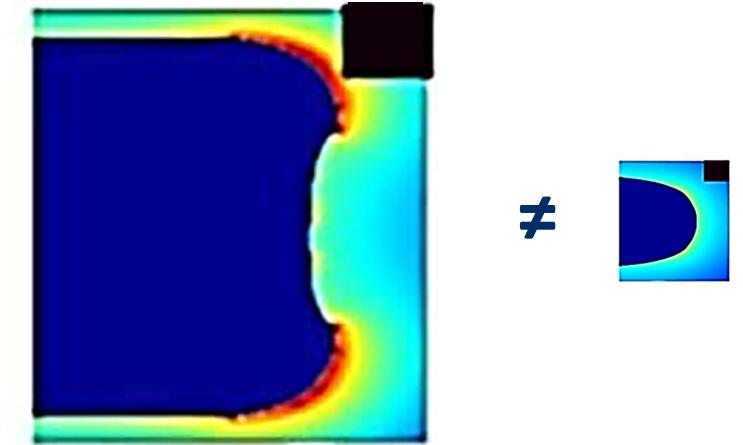
Laser effects



time ⏲

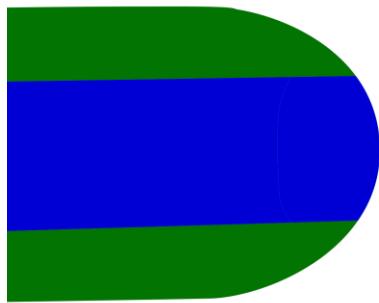


Shape affects electric field

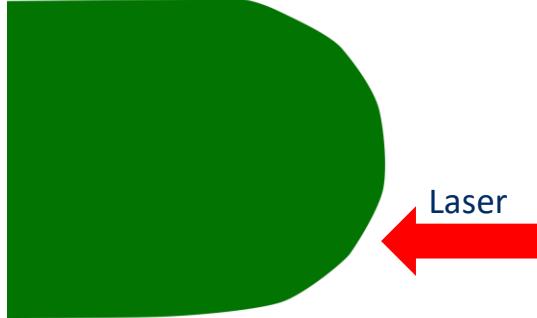


Complex reality of APT

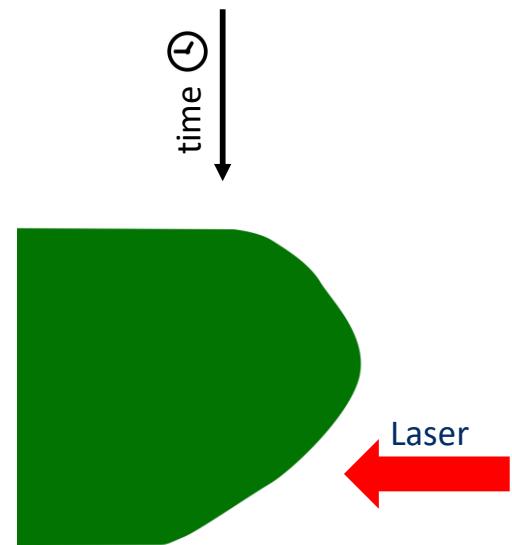
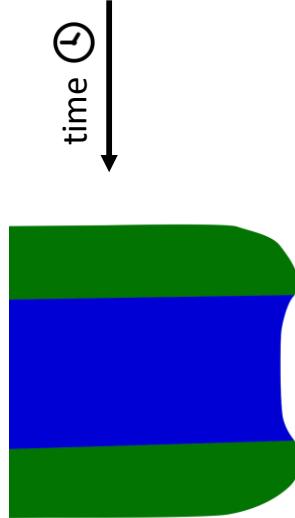
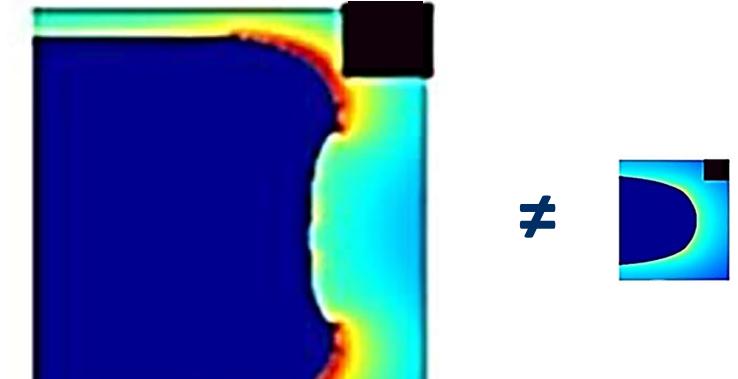
Material effects



Laser effects



Shape affects electric field

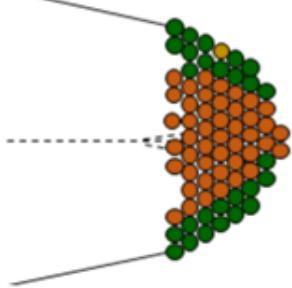


Research aim

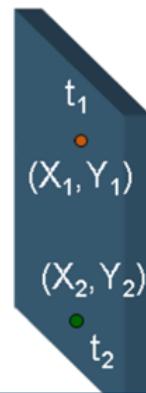
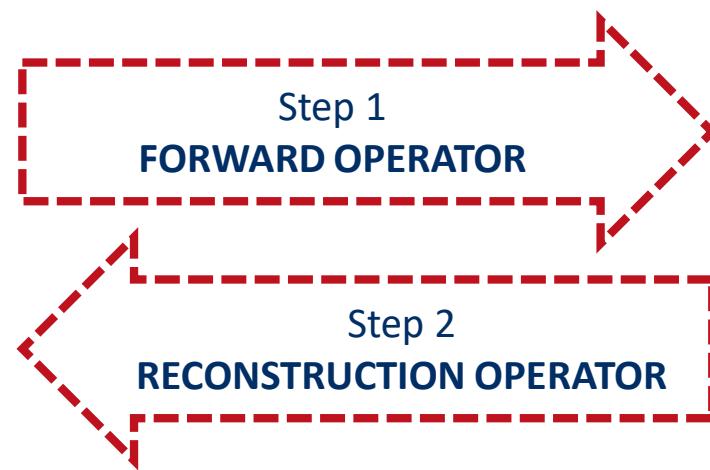
What?

Develop an **accurate** reconstruction model

How?

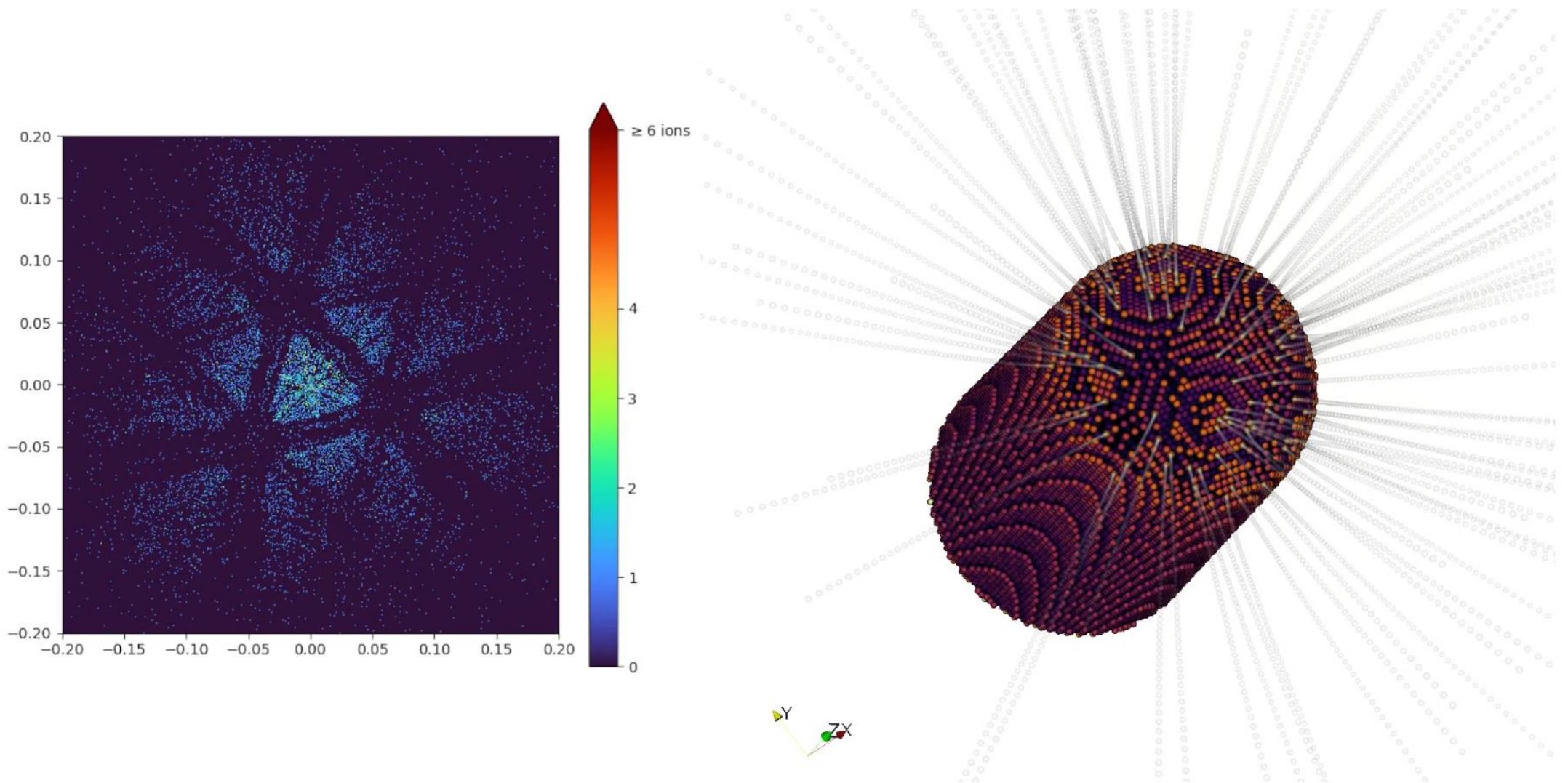


Specimen

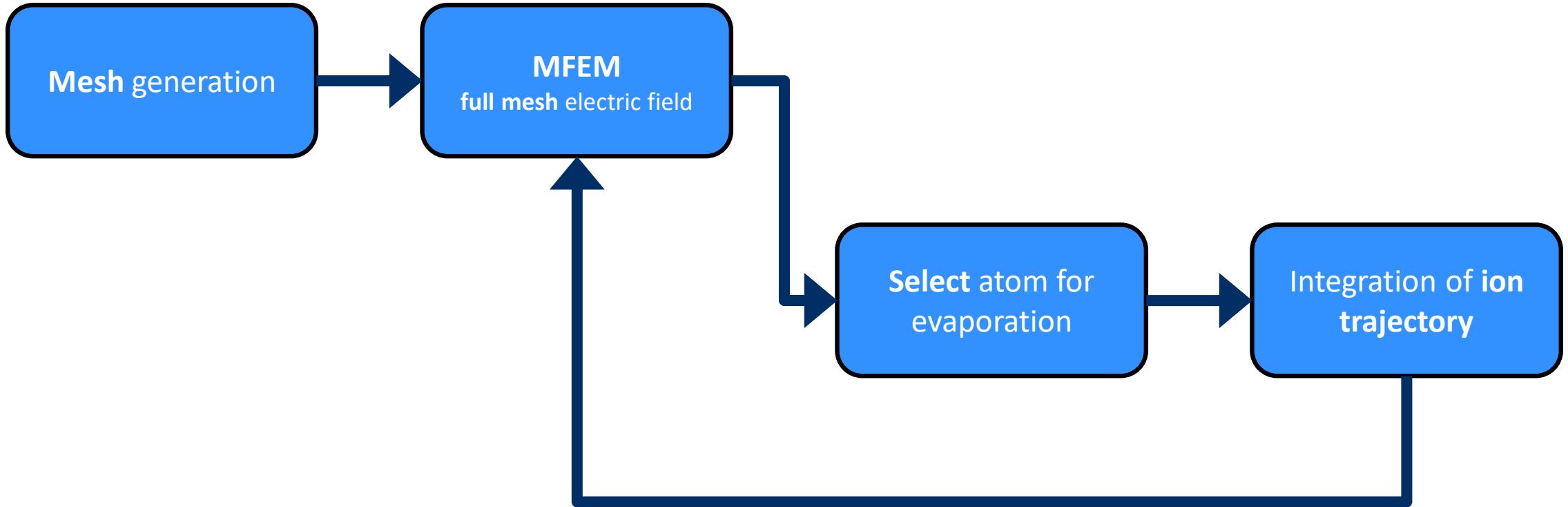


Ions on detector

Forward operator: Atom probe simulation based on FEM



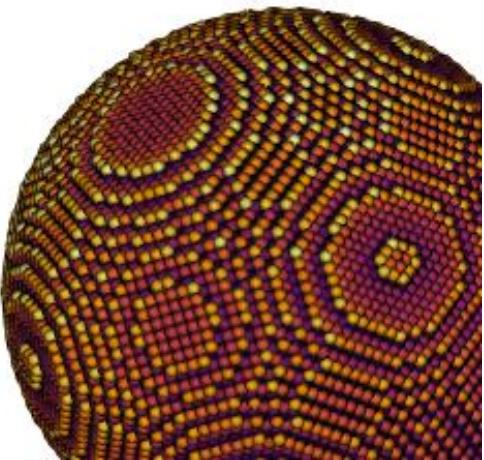
Forward operator: Atom probe simulation based on FEM



Mesh generation

Atom vertices

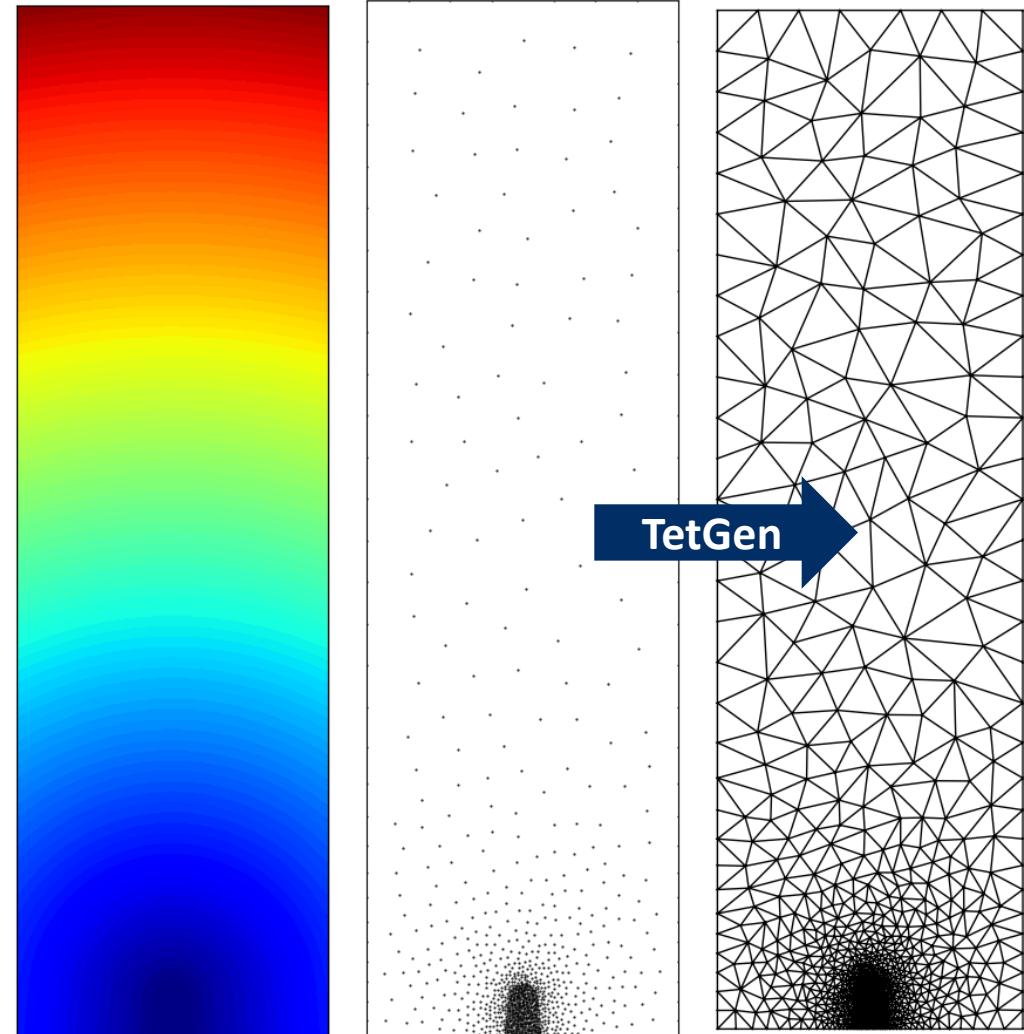
- Specimen size: 10s of nm
- Each atom locus in the specimen is represented by one mesh vertex
- This way we can capture the geometric protrusion of single atoms due to “terraces”



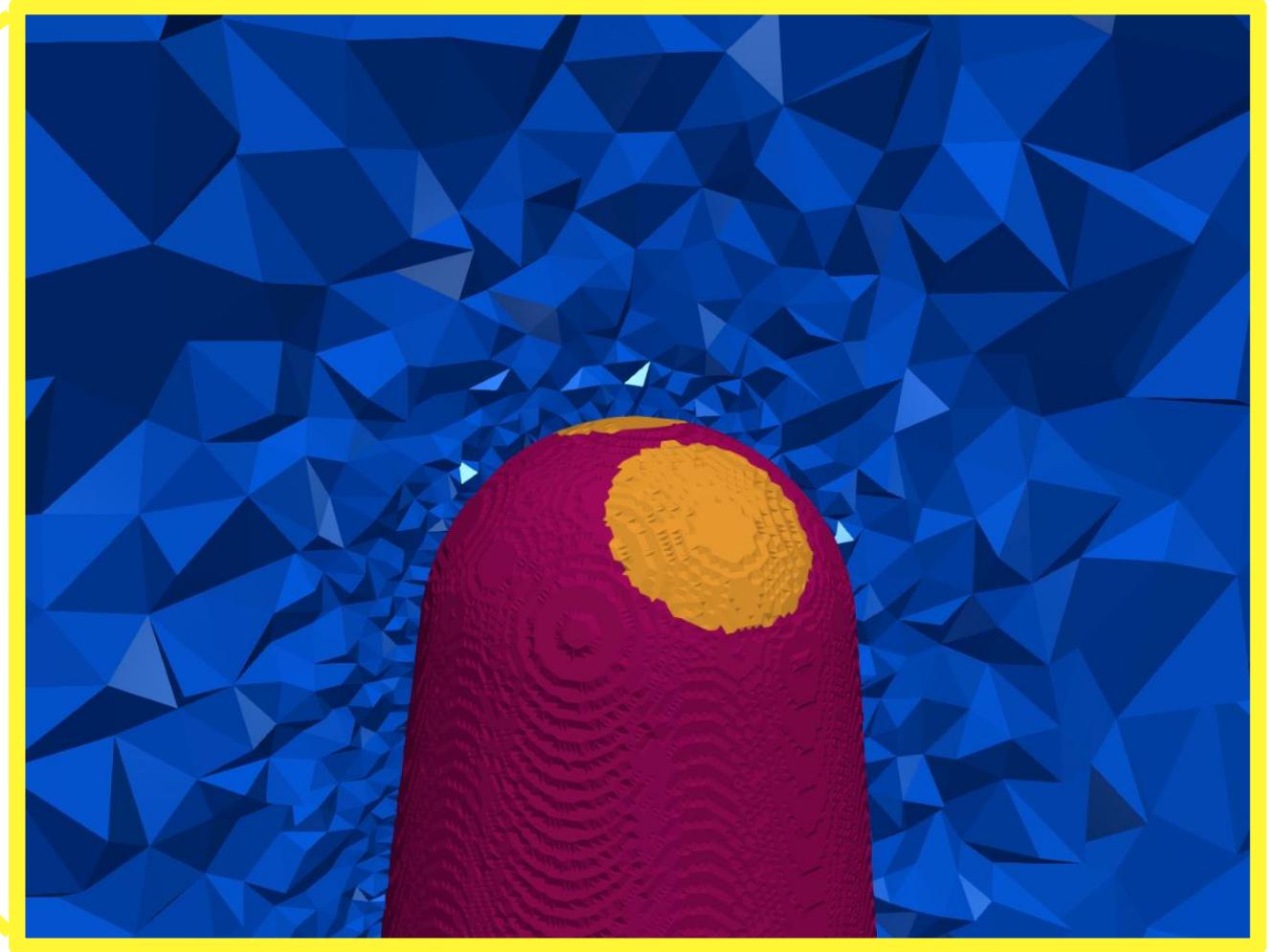
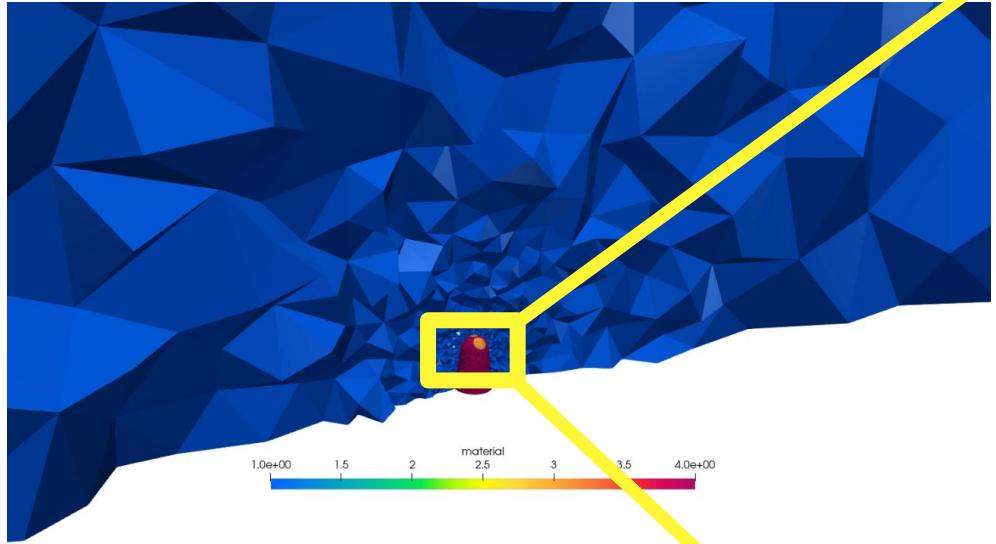
Vacuum vertices

- Vacuum chamber size: ~10cm
- Continuous resolution vertex placement method:
“Tree-based variable density Poisson Disk Sampling”

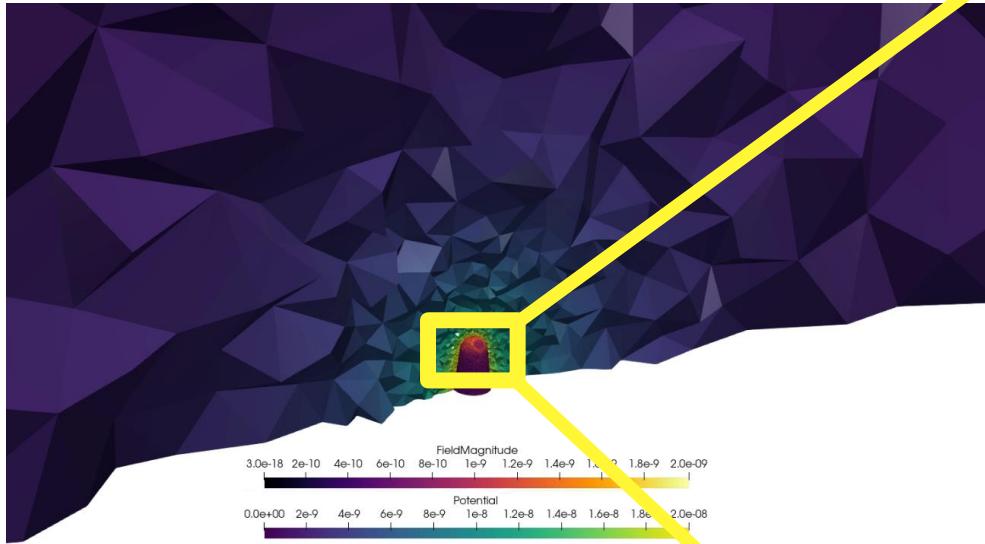
	Relative volume	% of vertices
Vacuum	> 99%	2%
Atoms	< 1%	98%



Mesh generation: Variable density Poisson disk sampling



MFEM: Electric field calculation

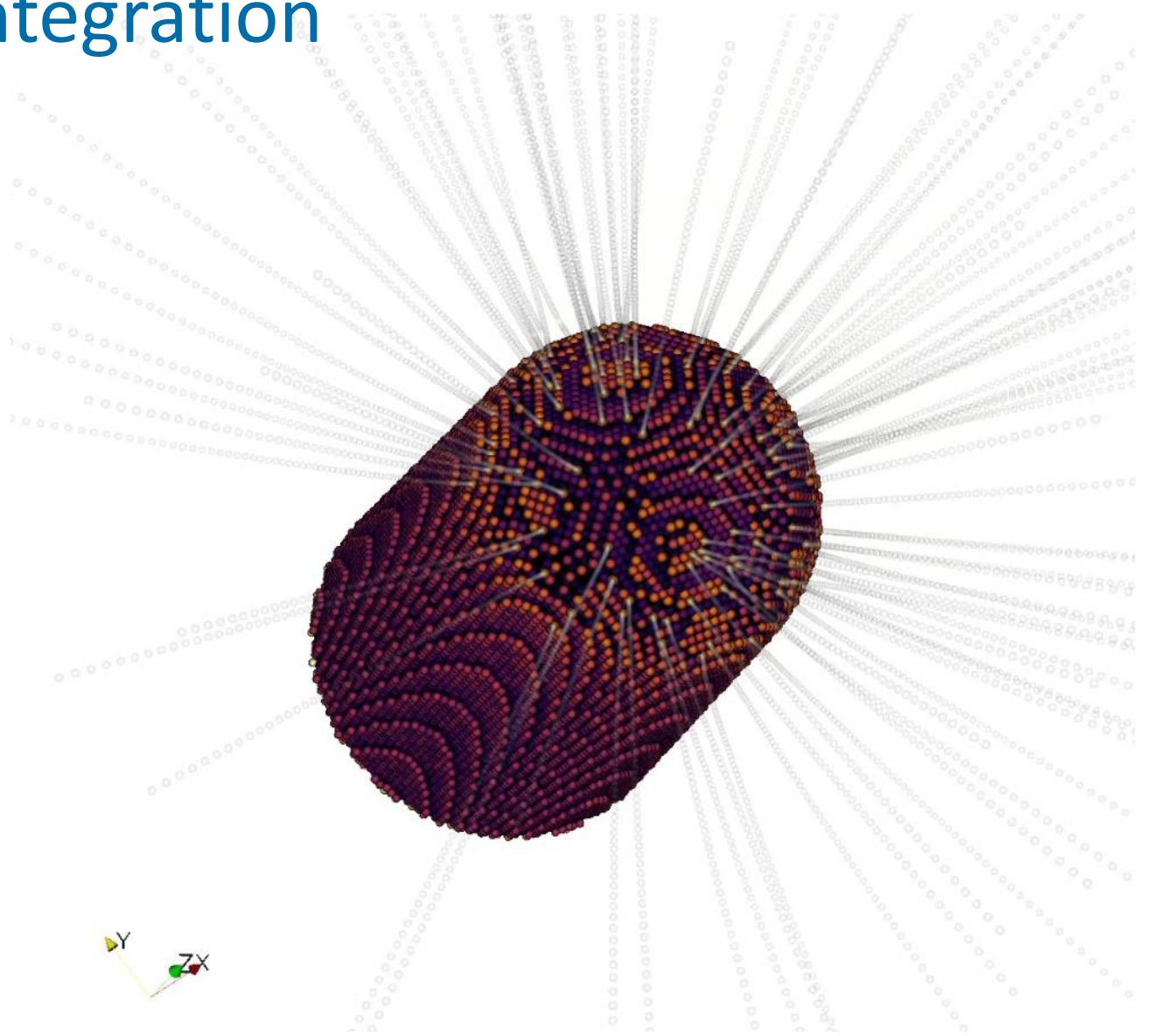
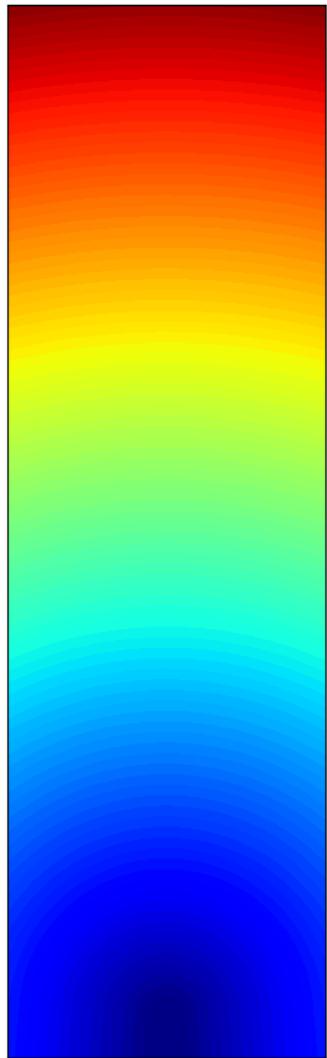


- Potential
H1 FESpace + DiffusionIntegrator + PCG
- Field [= -grad(Potential)]
H1 FESpace + DerivativeIntegrator + PCG
(Want to know field at vertex locations)

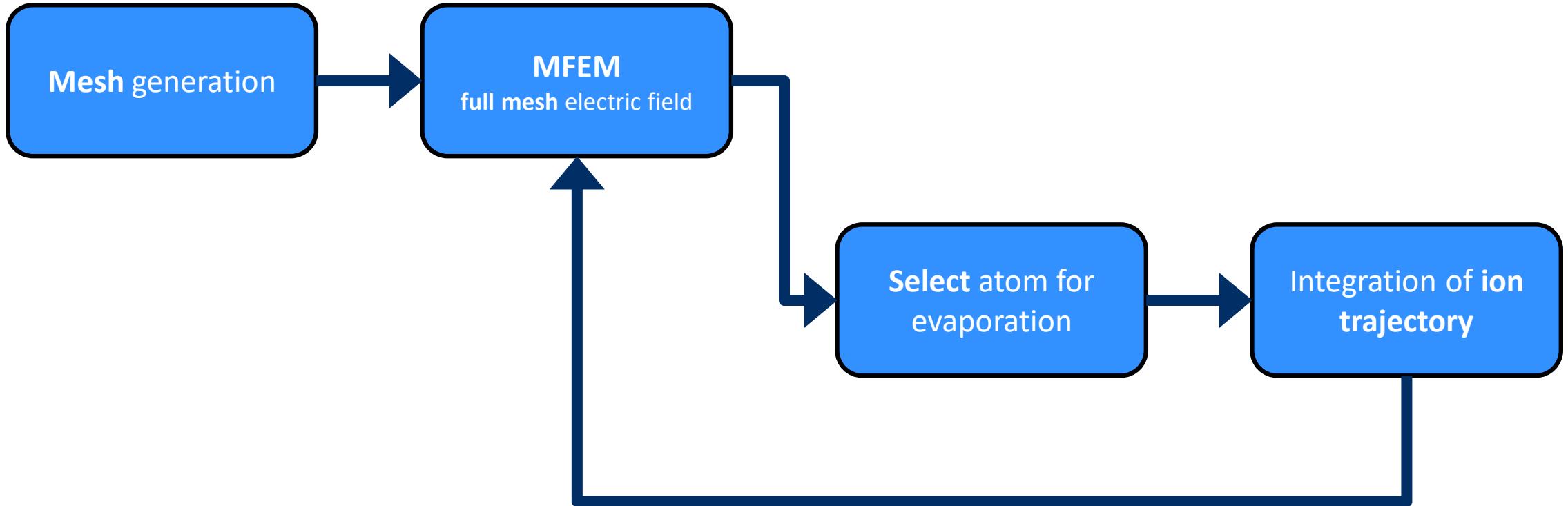


Selection and trajectory integration

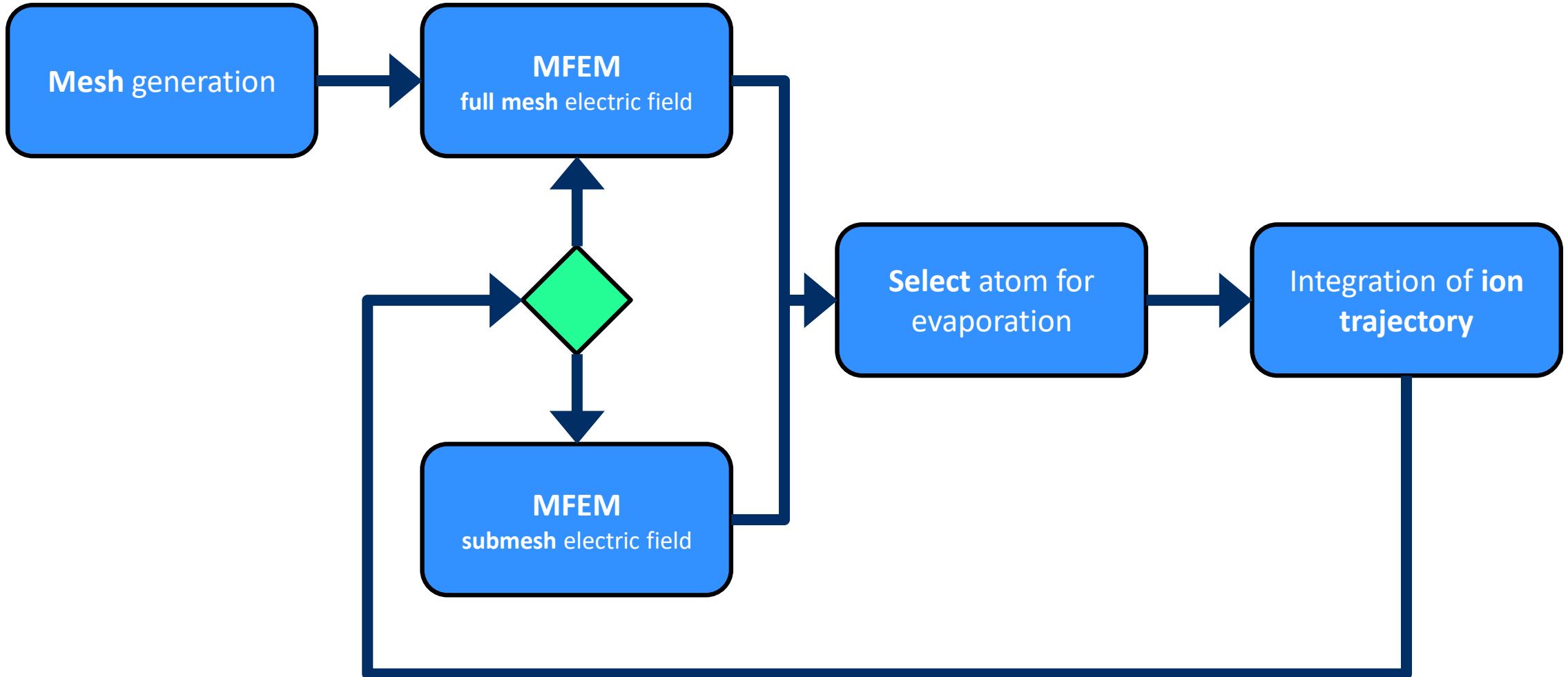
- Forward Euler
- **Variable** time steps



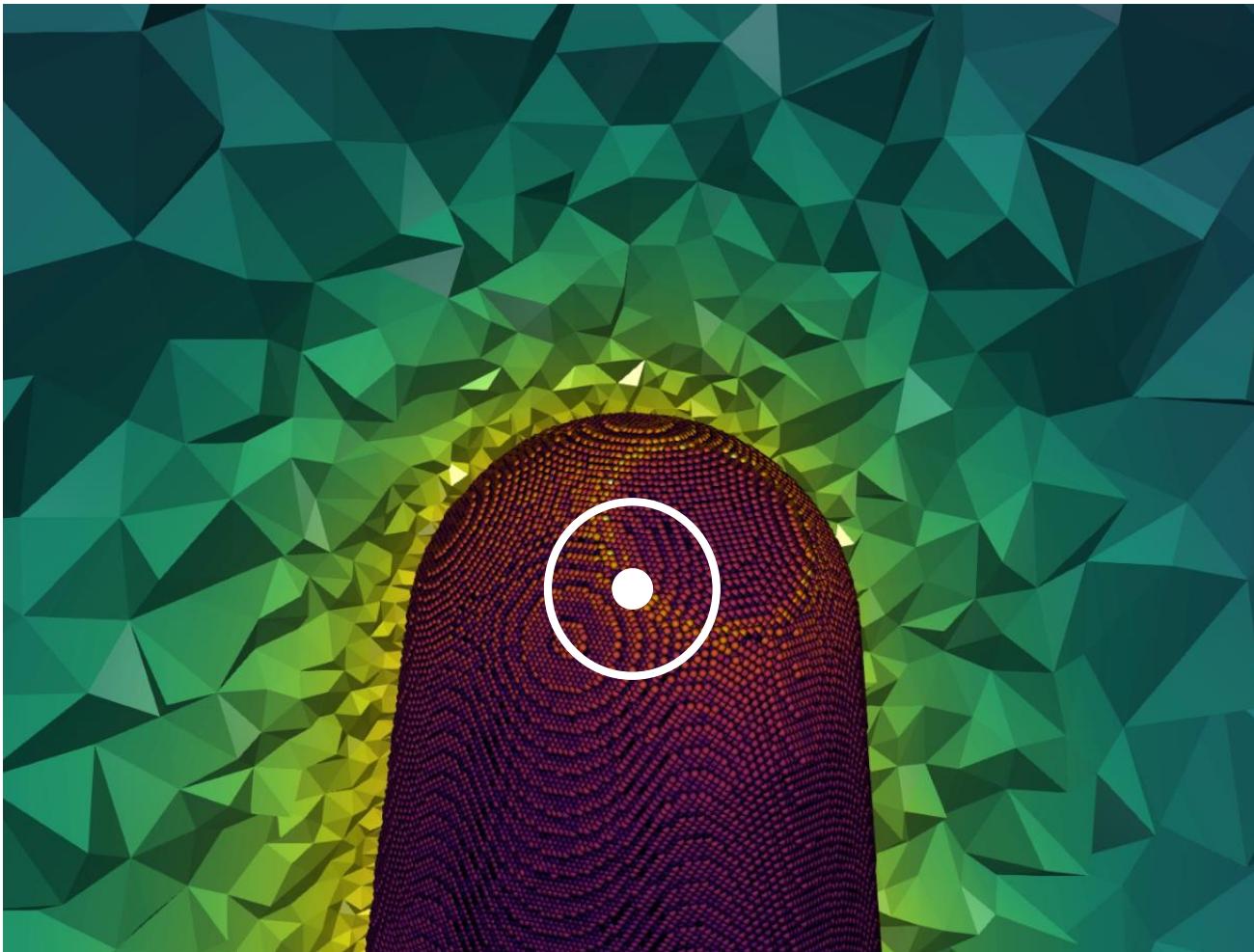
Forward operator: Atom probe simulation based on FEM



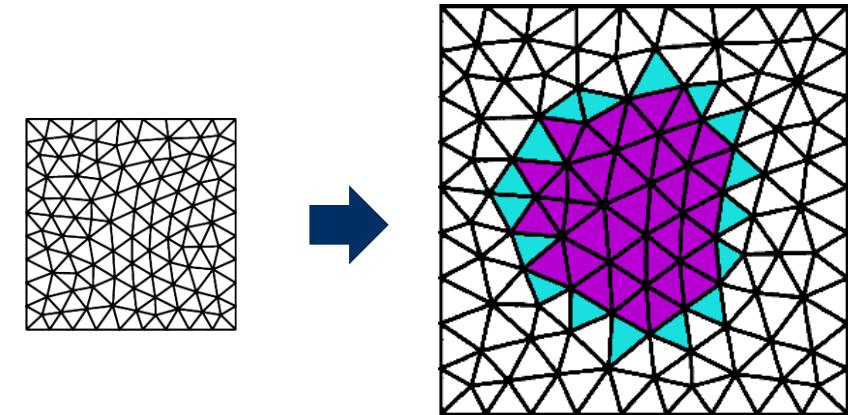
Forward operator: Atom probe simulation based on FEM



Submesh iterations



- Evaporation **changes** the electric field
- This change only occurs **close** to the evaporation site

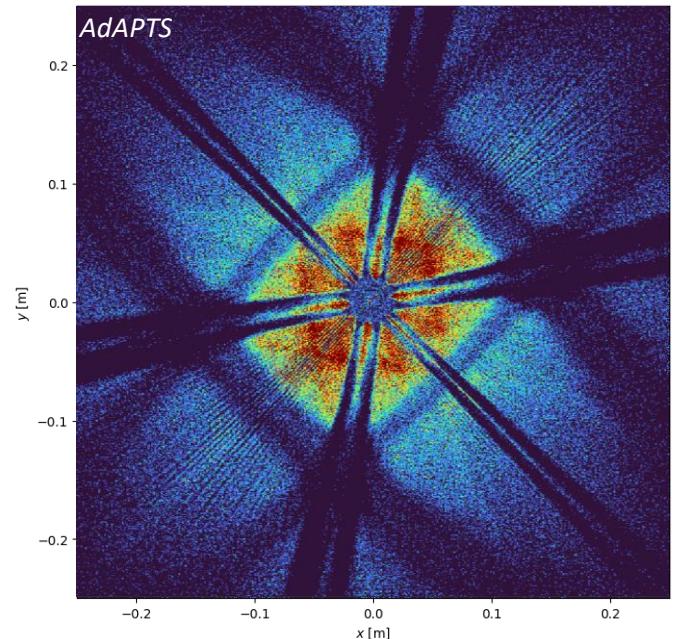
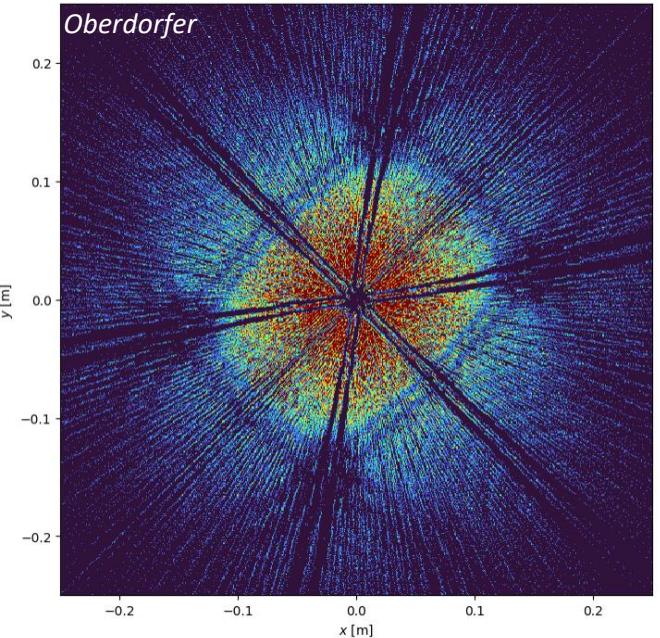
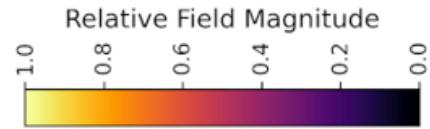
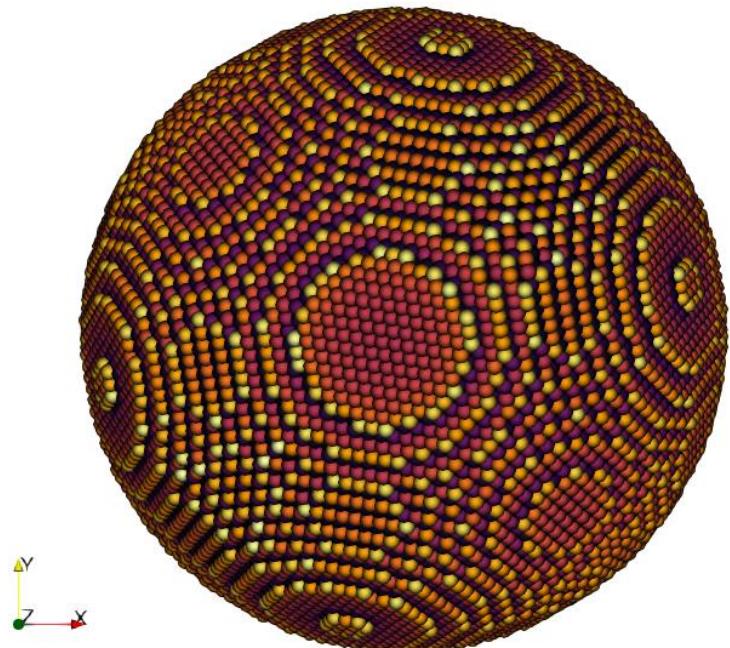


Comparison to Oberdorfer *et al.*

Tool	Time
Oberdorfer	6h 18min
AdAPTS (ours)	1h 20min



Almost
5x as fast





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Thank you for your attention

More questions? julian.luken@uantwerpen.be

References

1. Bas, P. *et al.*, **A general protocol for the reconstruction of 3D atom probe data**, 1995, *Applied Surface Science* , Vol. 87-88, Elsevier BV, p. 298-304, 10.1016/0169-4332(94)00561-3
2. Fletcher, C., **Model-driven reconstruction in atom probe tomography**, 2021, PhD thesis
3. Oberdorfer, C. *et al.*, **A full-scale simulation approach for atom probe tomography**, 2013, *Ultramicroscopy*, Vol. 128, Elsevier BV, p. 55-67, 10.1016/j.ultramic.2013.01.005
4. Gault, B. *et al.*, **Atom Probe Microscopy**, 2012, Springer New York, 10.1007/978-1-4614-3436-8, 10.1016/j.ultramic.2013.01.005
5. Dwork, N. *et al.*, **Fast variable density Poisson-disc sample generation with directional variation for compressed sensing in MRI**, 2021, *Magnetic Resonance Imaging*, Vol. 77, Elsevier BV, p. 186-193, 10.1016/j.mri.2020.11.012
6. Anderson, R. *et al.*, **MFEM: A modular finite element methods library**, 2021, *Computers & Mathematics with Applications*, Vol. 81, Elsevier BV, p. 42-74, 10.1016/j.camwa.2020.06.009
7. Si, H., **TetGen, towards a quality tetrahedral mesh generator**, 2013, Weierstraß-Institut für Angewandte Analysis und Stochastik Berlin, 10.34657/3337
8. Gault, B. *et al.*, **Atom probe tomography**, 2021, *Nature Reviews Methods Primers*, Vol. 1, No. 1, Springer Science and Business Media LLC, 10.1038/s43586-021-00047-w
9. Ashton, M. *et al.*, **Ab initio Description of Bond Breaking in Large Electric Fields**, 2020, *Physical Review Letters* , Vol. 124, No. 17, American Physical Society (APS), p. 176801, 10.1103/physrevlett.124.176801